



Atomic Force Microscope (AFM)

AFM is an extremely precise microscope that images a sample by rapidly moving a probe with a nanometer-sized tip across its surface. The AFM system can be operated in contact mode and non-contact mode.

AFM can make measurements in three dimensions, x, y, and z (normal to the sample surface), thus enabling the presentation of three-dimensional images of a sample surface. Quantitative measurement such as surface roughness and adhesion force can be performed on AFM.

AFM requires neither a vacuum environment nor any special sample preparation.

For enquiries, please contact the staff-in-charge.
Name: Ms. Pearlyn See
Phone: 67904851
Email: sysee@ntu.edu.sg

Usage Rate: [Key Equipment Charges For CESEL.xlsx](#)